

HiPerFET™ Power MOSFET

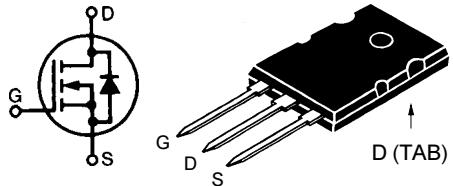
Single MOSFET Die

| | V_{DSS} | I_{D25} | $R_{DS(on)}$ | t_{rr} |
|-------------------|-----------|-----------|--------------|----------|
| IXFN 55N50 | 500V | 55A | 85mΩ | 250ns |
| IXFN 50N50 | 500V | 50A | 100mΩ | 250ns |
| IXFK 55N50 | 500V | 55A | 85mΩ | 250ns |
| IXFK 50N50 | 500V | 50A | 100mΩ | 250ns |

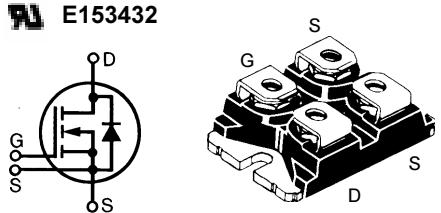
| Symbol | Test Conditions | Maximum Ratings | | |
|-------------|---|--|---------------|--------------------------------------|
| | | IXFK 55N50 | IXFK 50N50 | |
| V_{DSS} | $T_J = 25^\circ\text{C}$ to 150°C | 500 | | 500 V |
| V_{DGR} ① | $T_J = 25^\circ\text{C}$ to 150°C | 500 | | 500 V |
| V_{GS} | Continuous | ± 20 | | ± 20 V |
| V_{GSM} | Transient | ± 30 | | ± 30 V |
| I_{D25} | $T_c = 25^\circ\text{C}$ | 55 | 50 | 55 A |
| I_{DM} ② | $T_c = 25^\circ\text{C}$, | 220 | 200 | 220 A |
| I_{AR} | $T_c = 25^\circ\text{C}$ | 55 | 50 | 50 A |
| E_{AR} | $T_c = 25^\circ\text{C}$ | 60 | | 60 mJ |
| dv/dt | $I_s \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$ $T_J \leq 150^\circ\text{C}$, $R_G = 2 \Omega$ | 5 | | 5 V/ns |
| P_D | $T_c = 25^\circ\text{C}$ | 560 | | 600 W |
| T_J | | -55 ... +150 | | $^\circ\text{C}$ |
| T_{JM} | | 150 | | $^\circ\text{C}$ |
| T_{stg} | | -55 ... +150 | | $^\circ\text{C}$ |
| T_L | 1.6 mm (0.063 in) from case for 10 s | 300 | N/A | $^\circ\text{C}$ |
| V_{ISOL} | $50/60 \text{ Hz, RMS}$ $I_{ISOL} \leq 1 \text{ mA}$ | $t = 1 \text{ min}$ $t = 1 \text{ s}$ | N/A N/A | 2500 V~ 3000 V~ |
| M_d | Mounting torque Terminal connection torque | 0.9/6 N/A | | 1.5/13 Nm/lb.in. 1.5/13 Nm/lb.in. |
| Weight | | 10 | 30 | g |

| Symbol | Test Conditions | Characteristic Values | | |
|--|--|---|--------|---------------------------|
| | | Min. | Typ. | Max. |
| ($T_J = 25^\circ\text{C}$, unless otherwise specified) | | | | |
| V_{DSS} | $V_{GS} = 0 \text{ V}$, $I_D = 5 \text{ mA}$ V_{DSS} temperature coefficient | 500 | | V |
| | | | 0.096 | %/K |
| $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = 8 \text{ mA}$ $V_{GS(th)}$ temperature coefficient | 2 | | 4 V |
| | | | -0.201 | %/K |
| I_{GSS} | $V_{GS} = \pm 20 \text{ V}$; $V_{DS} = 0 \text{ V}$ | | | ± 200 nA |
| I_{DSS} | $V_{DS} = 0.8 \cdot V_{DSS} \text{ V}$ $V_{GS} = 0 \text{ V}$ | $T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$ | | 400 μA 2 mA |
| $R_{DS(on)}$ | $V_{GS} = 10 \text{ V}$, $I_D = 0.5 \cdot I_{D25}$ Pulse test, $t \leq 300 \text{ ms}$, duty cycle d $\leq 2 \%$ | 55N50 50N50 | | 85 mΩ 100 mΩ |

TO-264 AA (IXFK)



miniBLOC, SOT-227 B (IXFN)



G = Gate D = Drain
S = Source TAB = Drain

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

Features

- International standard packages
- Encapsulating epoxy meets UL 94 V-0, flammability classification
- miniBLOC with Aluminium nitride isolation
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

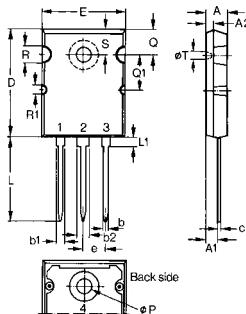
Applications

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls

Advantages

- Easy to mount
- Space savings
- High power density

| Symbol | Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified) | Characteristic Values | | |
|--------------|---|-----------------------|------|------|
| | | Min. | Typ. | Max. |
| g_{fs} | $V_{DS} = 10 \text{ V}; I_D = 0.5 \cdot I_{D25}$, pulse test | 45 | | S |
| C_{iss} | | 9447 | | pF |
| C_{oss} | $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ | 1260 | | pF |
| C_{rss} | | 611 | | pF |
| $t_{d(on)}$ | | 39 | | ns |
| t_r | | 70 | | ns |
| $t_{d(off)}$ | $R_G = 1 \Omega$ (External), | 153 | | ns |
| t_f | | 73 | | ns |
| $Q_{g(on)}$ | | 445 | | nC |
| Q_{gs} | | 54 | | nC |
| Q_{gd} | | 235 | | nC |
| R_{thJC} | TO-264 AA | | 0.22 | K/W |
| R_{thCK} | TO-264 AA | 0.15 | | K/W |
| R_{thJC} | miniBLOC, SOT-227 B | | 0.21 | K/W |
| R_{thCK} | miniBLOC, SOT-227 B | 0.05 | | K/W |

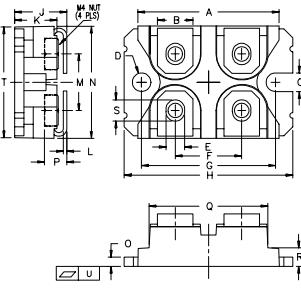
TO-264 AA Outline


| Dim. | Millimeter Min. | Millimeter Max. | Inches Min. | Inches Max. |
|------|--------------------|--------------------|----------------|----------------|
| A | 4.82 | 5.13 | .190 | .202 |
| A1 | 2.54 | 2.89 | .100 | .114 |
| A2 | 2.00 | 2.10 | .079 | .083 |
| b | 1.12 | 1.42 | .044 | .056 |
| b1 | 2.39 | 2.69 | .094 | .106 |
| b2 | 2.90 | 3.09 | .114 | .122 |
| c | 0.53 | 0.83 | .021 | .033 |
| D | 25.91 | 26.16 | 1.020 | 1.030 |
| E | 19.81 | 19.96 | .780 | .786 |
| e | 5.46 | BSC | .215 | BSC |
| J | 0.00 | 0.25 | .000 | .010 |
| K | 0.00 | 0.25 | .000 | .010 |
| L | 20.32 | 20.83 | .800 | .820 |
| L1 | 2.29 | 2.59 | .090 | .102 |
| P | 3.17 | 3.66 | .125 | .144 |
| Q | 6.07 | 6.27 | .239 | .247 |
| Q1 | 8.38 | 8.69 | .330 | .342 |
| R | 3.81 | 4.32 | .150 | .170 |
| R1 | 1.78 | 2.29 | .070 | .090 |
| S | 6.04 | 6.30 | .238 | .248 |
| T | 1.57 | 1.83 | .062 | .072 |

Source-Drain Diode
 $(T_J = 25^\circ\text{C}$, unless otherwise specified)

| Symbol | Test Conditions | Characteristic Values | | |
|----------------------------------|---|-----------------------|------------|--------------------------|
| | | Min. | Typ. | Max. |
| I_s | $V_{GS} = 0$ | 55N50 50N50 | 55 50 | A A |
| I_{SM} | Repetitive; pulse width limited by T_{JM} | 55N50 50N50 | 220 200 | A A |
| V_{SD} | $I_F = 100 \text{ A}, V_{GS} = 0 \text{ V},$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$ | | 1.5 | V |
| t_{rr} Q_{RM} I_{RM} | $I_F = 50 \text{ A}, -di/dt = 100 \text{ A}/\mu\text{s}, V_R = 100 \text{ V}$ | 209 1.4 13 | | ns μC A |

- Notes:
- $R_{GS} = 1 \text{ M}\Omega$
 - Pulse width limited by T_{JM} .

miniBLOC, SOT-227 B


M4 screws (4x) supplied

| Dim. | Millimeter Min. | Millimeter Max. | Inches Min. | Inches Max. |
|------|--------------------|--------------------|----------------|----------------|
| A | 31.50 | 31.88 | 1.240 | 1.255 |
| B | 7.80 | 8.20 | 0.307 | 0.323 |
| C | 4.09 | 4.29 | 0.161 | 0.169 |
| D | 4.09 | 4.29 | 0.161 | 0.169 |
| E | 4.09 | 4.29 | 0.161 | 0.169 |
| F | 14.91 | 15.11 | 0.587 | 0.595 |
| G | 30.12 | 30.30 | 1.186 | 1.193 |
| H | 38.00 | 38.23 | 1.496 | 1.505 |
| J | 11.68 | 12.22 | 0.460 | 0.481 |
| K | 8.92 | 9.60 | 0.351 | 0.378 |
| L | 0.76 | 0.84 | 0.030 | 0.033 |
| M | 12.60 | 12.85 | 0.496 | 0.506 |
| N | 25.15 | 25.42 | 0.990 | 1.001 |
| O | 1.98 | 2.13 | 0.078 | 0.084 |
| P | 4.95 | 5.97 | 0.195 | 0.235 |
| Q | 26.54 | 26.90 | 1.045 | 1.059 |
| R | 3.94 | 4.42 | 0.155 | 0.174 |
| S | 4.72 | 4.85 | 0.186 | 0.191 |
| T | 24.59 | 25.07 | 0.968 | 0.987 |
| U | -0.05 | 0.1 | -0.002 | 0.004 |

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715
4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025

Figure 1. Output Characteristics at 25°C

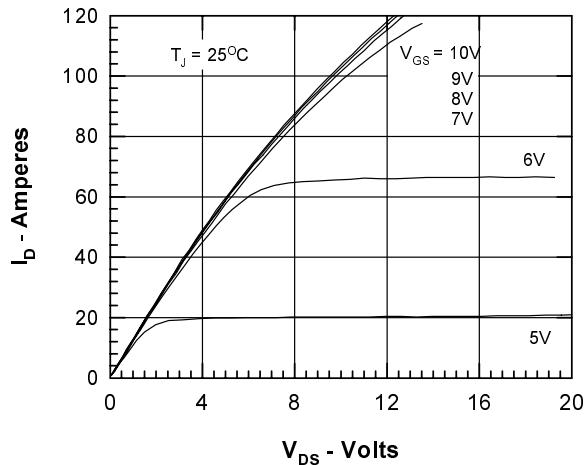


Figure 3. $R_{DS(on)}$ normalized to 0.5 I_{D25} value vs. I_D

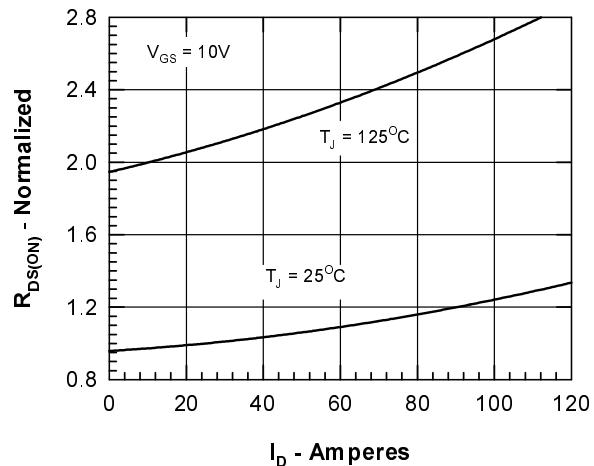


Figure 5. Drain Current vs. Case Temperature

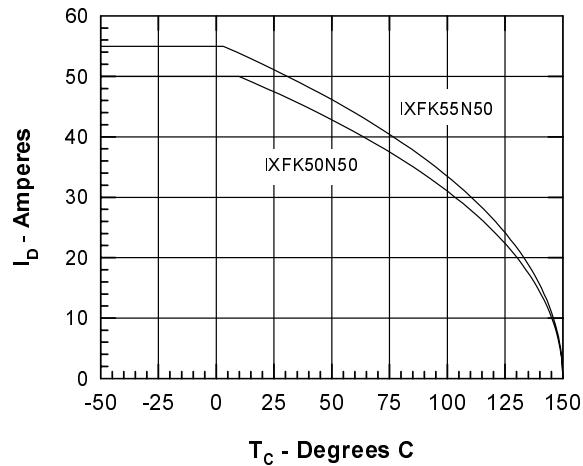


Figure 2. Output Characteristics at 125°C

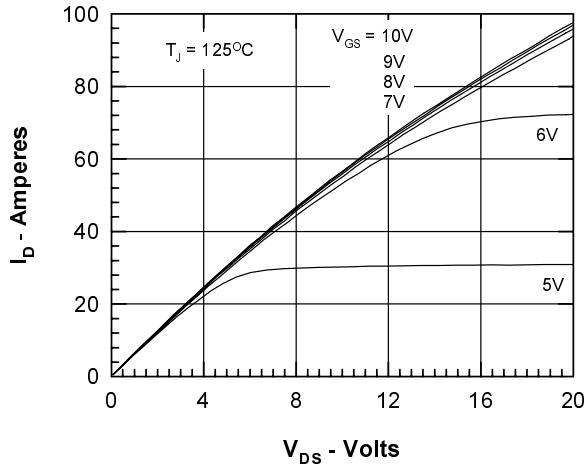


Figure 4. $R_{DS(on)}$ normalized to 0.5 I_{D25} value vs. T_J

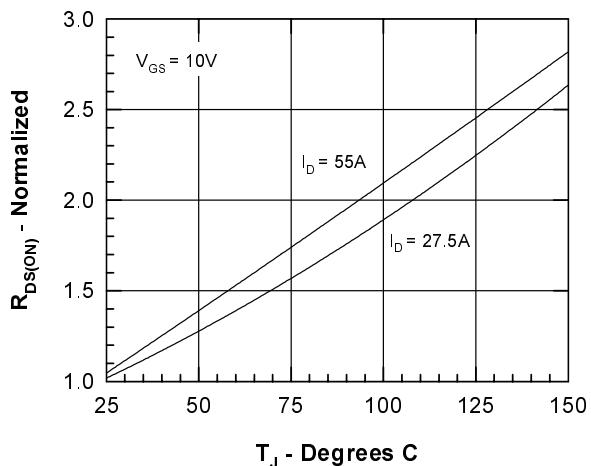


Figure 6. Admittance Curves

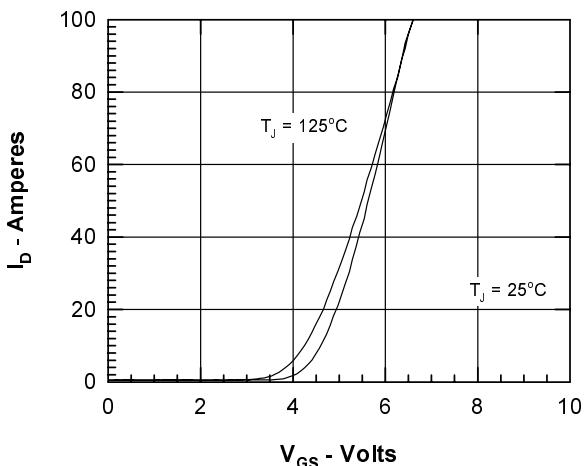


Figure 7. Gate Charge

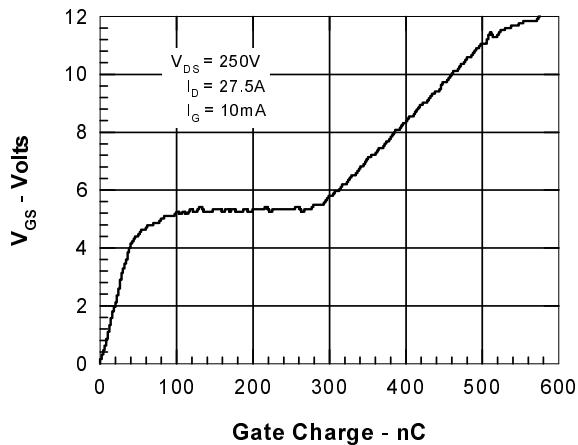


Figure 8. Capacitance Curves

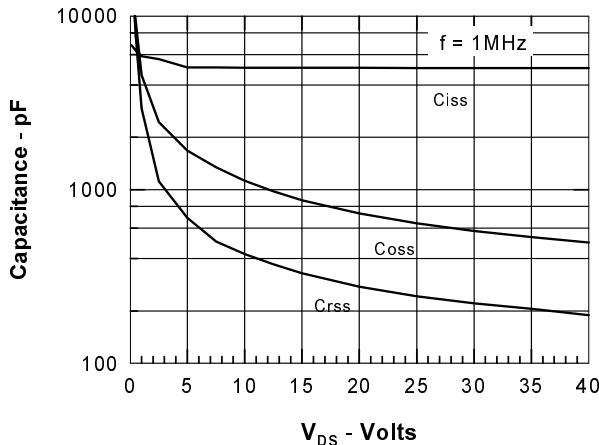


Figure 9. Forward Voltage Drop of the Intrinsic Diode

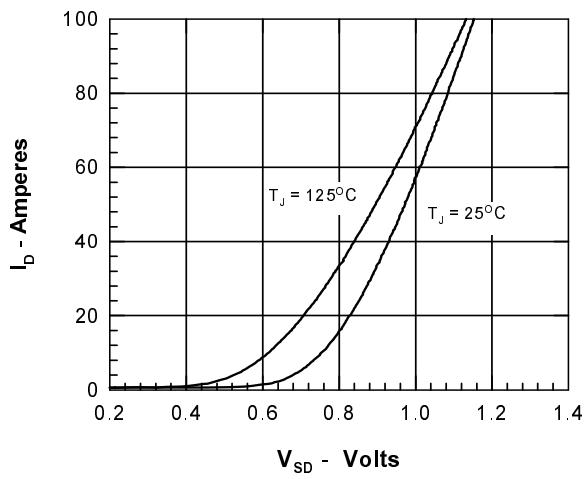


Figure 10. Forward Bias Safe Operating Area

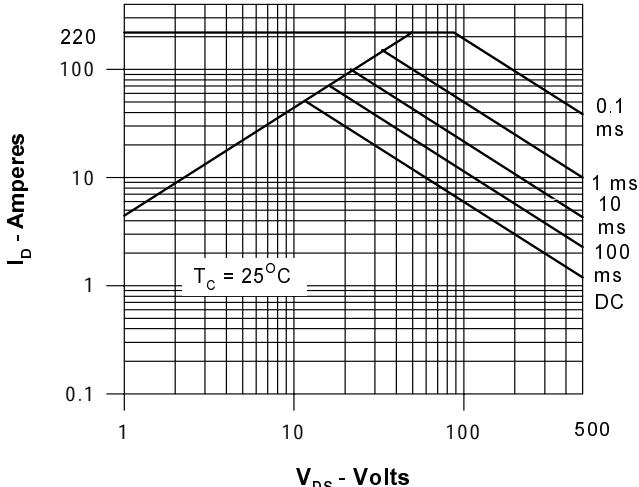


Figure 11. Transient Thermal Resistance

